Welcome to VTS 2007, the twenty-fifth in a series of annual symposia that focus on innovation in the field of testing of integrated circuits and systems.

The core of VTS 2007, the three day technical program, responds to the many trends and challenges in the semiconductor design and manufacturing industries with papers covering a diverse and seminal set of topics including, RF and Analog Test, Delay Test, Memory Test, Diagnosis, Online Test, SOC Test, and Fault Prediction and Evaluation.

In addition to the three-day technical program, VTS 2007 features special sessions, and the Innovative Practices track. These tracks highlight cutting-edge challenges faced by test practitioners, and innovative solutions employed to address them. Full-day tutorials and workshops are also held in conjunction with VTS 2007. The Open Source Test Technology Tools Workshop continues its association with VTS. So does the Wireless Test Workshop which will be co-located with VTS this year for a second time. Three tutorials are offered by the TTTC Tutorials & Education Group through the Test Technology Education Program (TTEP). The tutorials by leading VLSI test academics and practitioners provide an introduction to a diverse set of topics, including Delay Test, Timing Issues, and the Interactions of Design and Test. The tutorials provide opportunities for design and test professionals to update their knowledge-base in test, and earn official IEEE TTTC accreditation.

The social program at VTS provides an opportunity for informal technical discussions among participants. Berkeley, California, provides a highly attractive backdrop for all VTS 2007 activities.

VTS is the result of the work of many dedicated volunteers: the reviewers, the best paper award judges, the Program Committee, the Organizing Committee, and the Steering Committee. We wholeheartedly thank them all. We also wish to thank all the authors who submitted their research to VTS 2007, and the program participants for their contribution at the symposium. We thank the IEEE Computer Society Test Technology Technical Council for its continued sponsorship and support. And most importantly, we would like to offer a heartfelt word of thanks to all the Corporate Supporters of VTS 2007 who have contributed generously.

We hope that you will find VTS 2007 enlightening, thought-provoking, rewarding, and enjoyable. I wish you all a fun-filled and productive week in Berkeley and hope that you will keep making VTS a success by actively participating in it, assisting in its organization, and letting us always know when we can do something better. Thank you all for coming.

Paolo Prinetto  
General Chair

Alex Orailoglu  
Program Chair